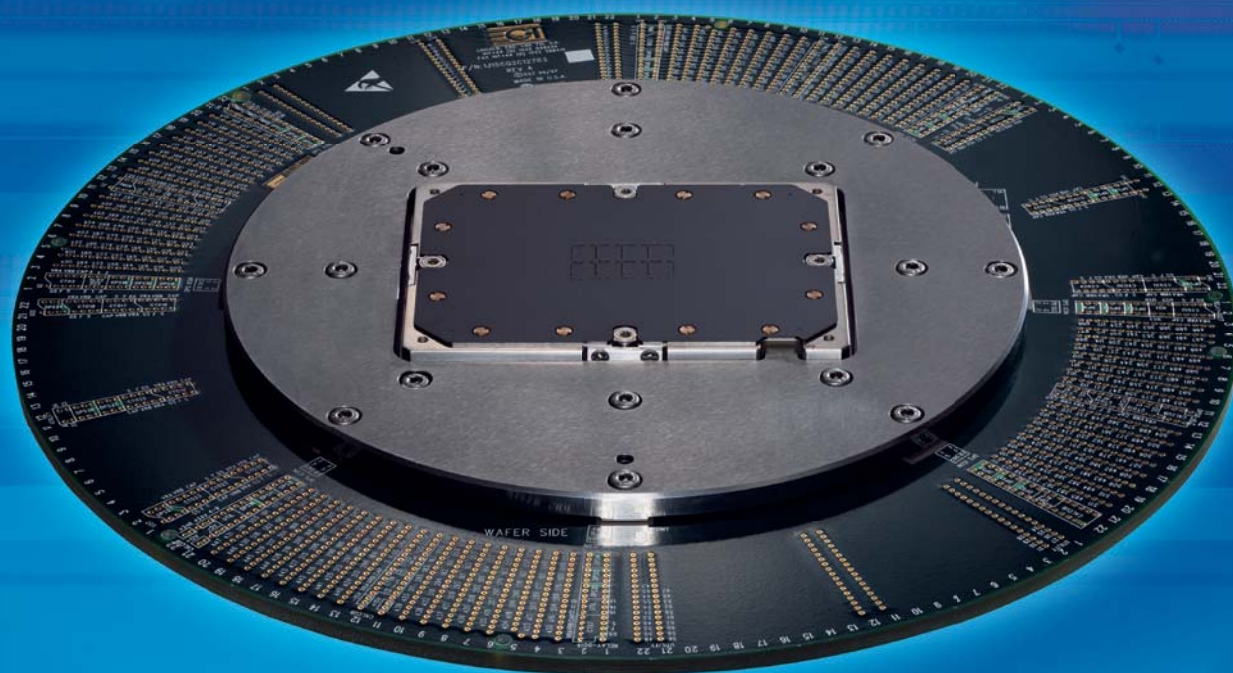


ViProbe® Space Transformer Series

Probe Cards for Wafer Test



FEINMETALL

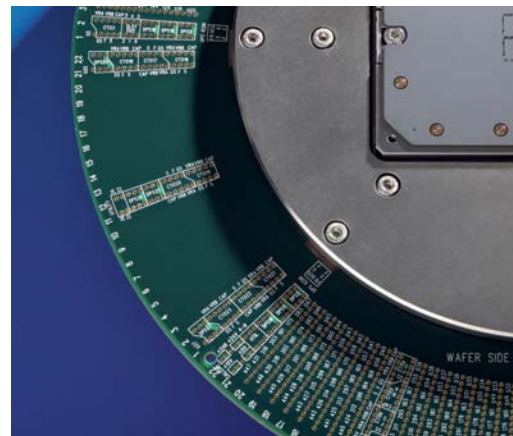
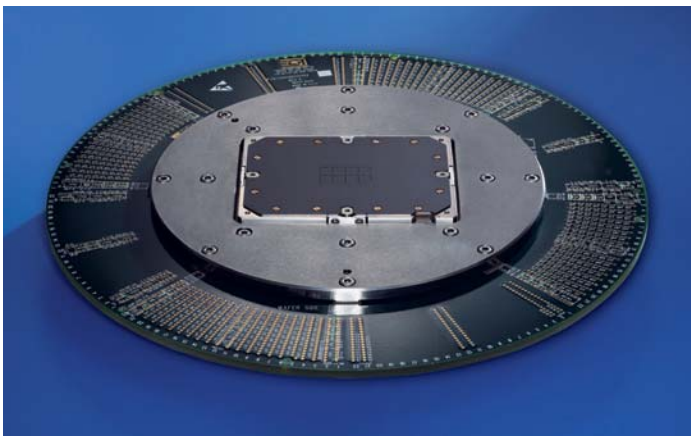
Contact technologies for electronics



ViProbe® Space Transformer Series

FEINMETALL ViProbe® Space Transformer Series represents a leading technology in advanced wafer probing. The advantages of our ViProbe® Space Transformer Series are excellent electrical performance, high pin count-, high parallel testing as well as excellent temperature behaviour.

ViProbe® Space Transformer Series products are based on MLC Technology. These products provide the capability for substantial time- and cost- savings in wafer testing.



7 good reasons for using ViProbe® Space Transformer Series the Vertical Probe Card Technology from Feinmetall

- Excellent electrical performance
- Easy Maintenance & Service
- Easy exchange of needles
- Precise alignment over the entire lifetime
- Excellent temperature behaviour
- Minimum impact on the bond pad
- Tolerates changing planarity conditions

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Key Parameters S22/S24

Active Area:	40x40mm (S22) 50x80mm (S24)
Tester:	Teradyne J750, µFlex Verigy V93000 other testers on request
Pitch:	min 59µm
Test points:	up to 8,000
Temperature:	-40°C...+180°C

Subject to change without notice

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